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Lena Cheung

/ Lena Cheung Date: 10/29/04

Customer No. 026418

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Docket No. GK-ZEI-3214 / 500343 20225

Applicant(s): Hans-Juergen DOBSCHAL, et al.

Application No.: 10/626,130

Group:

Filed: July 24, 2003

Examiner:

For: IMAGING SYSTEM FOR A MICROSCOPE BASED ON EXTREME ULTRAVIOLET (EUV) RADIATION

Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

**SECOND SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT**

S I R:

Applicant hereby submits the following European Search Report, German Search Report and references which were cited in counterpart European and German application:

	Document Number	Date	Name and/or Country	English Translation
AI	6,522,717	2/18/03	Katsuhiko Murakami, et al.	
AJ	5,848,119	12/8/98	Akira Miyake, et al.	
AK	5,719,915	2/17/98	Masaki Koike, et al.	
AL	6,118,577	9/12/00	William C. Sweatt, et al.	
AV	Article entitled: "High Energy X-Ray Phase Contrast Microscopy Using A Circular Bragg-Fresnel Lens" Optics Communications, North-Holland Publishing Co. Amsterdam, NL, Bd. 135, Nr. 4, 15 February 1997			

Also enclosed is Form PTO-1449 which lists the references along with a copy of the reference and a check for \$180.00.

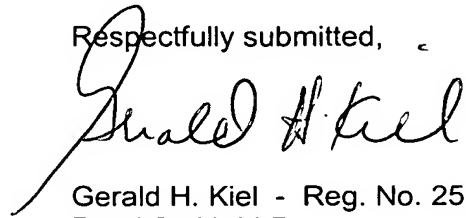
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This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted, c

A handwritten signature in black ink, appearing to read "Gerald H. Kiel". The signature is fluid and cursive, with a long, sweeping underline that extends to the left.

Gerald H. Kiel - Reg. No. 25,116
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Enclosures:

**LIST OF PRIOR ART CITED BY APPLICANT**
(Filed on January 15, 2004)Docket No. **GK-ZEI-3214 / 500343.20225**Applicant(s): **Hans-Juergen DOBSCHAL, Thomas SCHERUEBL, Robert BRUNNER, Norbert ROSENKRANZ and Joern GREIF-WUESTENBECKER**Application No. **10/626,130**Group: **2872**Filed: **July 24, 2003**Examiner: **Fayez ASSAF****U.S. PATENT DOCUMENTS**

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
	AI	6,522,717	2/18/03	Katsuhiko Murakami, et al.	378	43	
	AJ	5,848,119	12/8/98	Akira Miyake, et al.	378	34	
	AK	5,719,915	2/17/98	Masaki Koike, et al.	378	84	
	AL	6,118,577	9/12/00	William C. Sweatt, et al.	359	351	
	AM						
	AN						
	AO						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	CLASS	Sub-Class	Translation	
							YES	NO
	AP							
	AQ							
	AR							
	AS							
	AT							
	AU							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AV	Article entitled: "High Energy X-Ray Phase Contrast Microscopy Using A Circular Bragg-Fresnel Lens" Optics Communications, North-Holland Publishing Co. Amsterdam, NL, Bd. 135, Nr. 4, 15 February 1997
	AW	
	AX	
	AY	
	AZ	

Examiner:

Date:

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.